

Applicants:

Wayne Chen et al.

Assignee:

KLA-Tencor Corporation

Title:

System and Methods for Classifying Anomalies of Sample Surfaces

Application No.:

10/613,634

Filing Date:

July 3, 2003

Examiner:

Michael Patrick Stafira

Group Art Unit:

2877

Docket No.:

TNCR.178US1

Conf. No.:

4612

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

AMENDMENT

Sir:

This is in response to the Office Action dated July 28, 2004, setting a period for response expiring on October 28, 2004. A Petition for Extension of Time requesting a one-month extension is herewith enclosed to extend the period for response until November 29, 2004, November 28 being a Sunday.

Amendments to the Claims are not being made.

Amendments to the Specification begin on page 5 of this paper.

Amendments to the Drawings begin on page 6 of this paper.

Remarks begin on page 7 of this paper.

Attorney Docket No.: TNCR.178US1 Applicat

- 1 -

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